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(54) **TEST ACCESS CIRCUIT AND METHOD OF ACCESSING EMBEDDED TEST CONTROLLERS IN INTEGRATED CIRCUIT MODULES**

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LOGICVISION (CANADA), INC.**1525 CARLING AVENUE, SUITE 404****OTTAWA, ON K1Z 8R9 (CA)**(57) **ABSTRACT**

A test access circuit (TAC) for use in controlling test resources including child test access circuits (TACs) and/or test controllers, in an integrated circuit, comprises an enable input for enabling or disabling access to the test resources, a test port associated with each test resource, each test port including a test port enable output for connection to an enable input of an associated test resource; and an input for receiving a serial output of the associated test resource; and means for selecting a test resource for communication therewith.

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